

## MISS *SWIR* Spectrometer

MISS stands for Mini Imaging Spatial Spectrometer. This innovative spectrometer gives access to the spatially resolved spectrum of your sources. Thanks to its unique compactness, the MISS allows vertical and horizontal spatial chirp measurements at any position of your beam path. It can easily be integrated at different stages of amplified laser systems. Originally available with Si-based cameras, **the MISS now offers a unique solution to measure 2D spectrum of laser sources covering SWIR and VSWIR wavelength ranges, thanks to InGaAs-based detectors.**



### Key features

- ◆ Compact design
- ◆ Horizontal and vertical spatial chirp measurement
- ◆ User-friendly and powerful software
- ◆ High spatial and spectral resolution (sampling down to 6  $\mu\text{m}$  and 0.4 nm)
- ◆ Different models from 400 to 1700 nm
- ◆ Input beam diameter up to 12.5 mm
- ◆ Single shot capable up to 200 kHz
- ◆ Beam profiler function with CamSwitch option

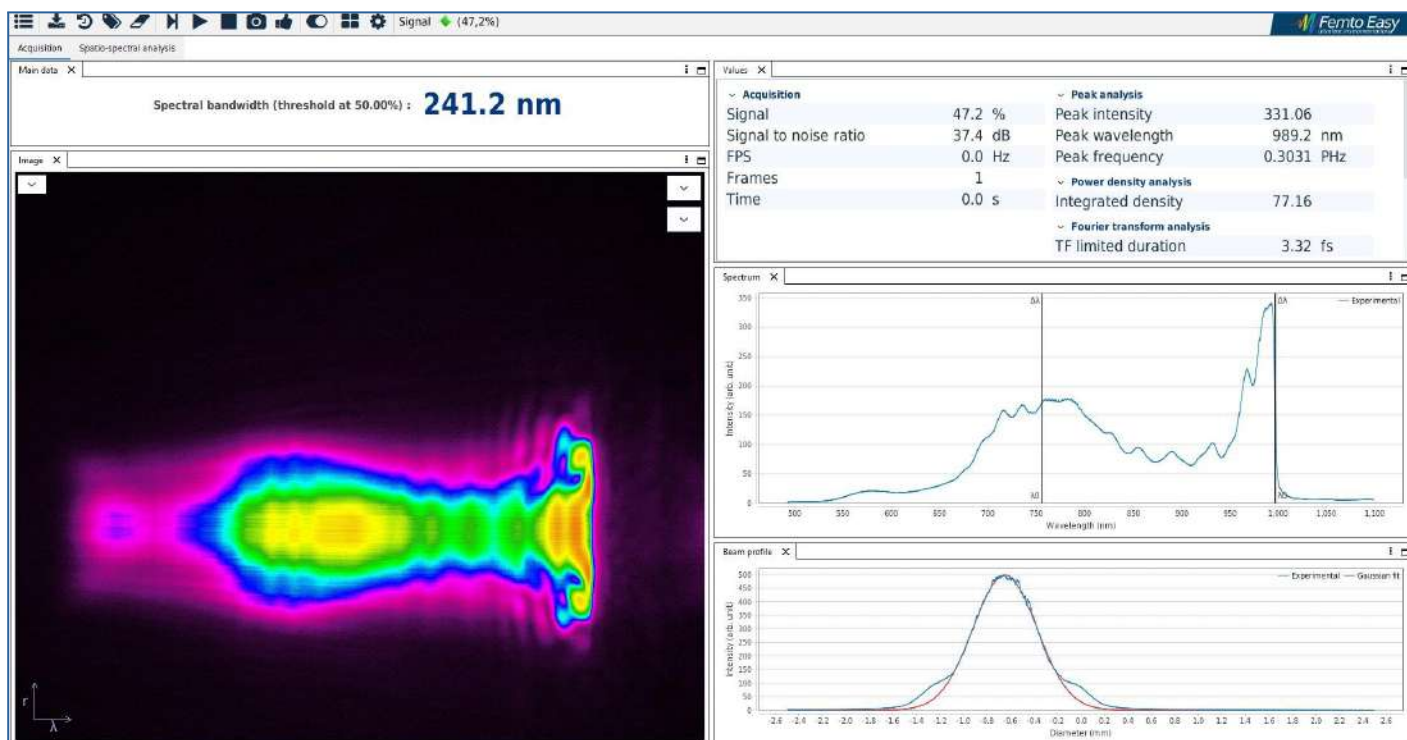
### Options

- ◆ Fiber input connector
- ◆ Trigger
- ◆ CamSwitch

# Specifications

Models	SWIR 320	SWIR 640	SWIR 1280	VSWIR 656 / L	VSWIR 1296 / L
Accessible spectral range (nm)	900 - 1700			400 - 1700	
Typical spectral window $\Delta\lambda$ (nm)	500	775	800	250 / 350	500 / 700
Camera resolution	320 x 256 0.08 Mpx	640 x 512 0.3 Mpx	1280 x 1024 1.3 Mpx	656 x 520 0.3 Mpx	1296 x 1032 1.3 Mpx
Spectral sampling (nm/px)	1.7	1.2	0.7	0.4- 0.6	
Optical spectral resolution (nm) <sup>1</sup>	3.5	3.5	2	1 / 1.5	
Input beam size (mm)	6.4	9.6	10.2	3.3 / 6.5	6.5 / 12.5
Max spatial resolution ( $\mu\text{m}$ )	25.0	19.0	10.0	6.3 / 12.5	
Exposure time min – max (ms)	0.01 – 500				
Shutter type	Global				
Detection	InGaAs 12 Bits				
PC Interface	USB 3.1				
Dimensions (mm)	117 x 102 x 52			101 x 101 x 52 / 117 x 102 x 52	

<sup>1</sup> resolution achieved on 80% of the spectral range  
Custom versions available on request



## STAR Software

- ◆ Live extraction of spatially resolved spectra, spatial chirp, spatially resolved Fourier limited pulse duration analysis, beam profile analysis...
- ◆ Enhanced background & hot pixels treatment, for optimum dynamic and signal to noise ratio
- ◆ Client / Server interface, allowing remote control through network
- ◆ All data exportable into most common formats